Form PTO 1640  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
249406US2SRDSERIAL NO.  
10/786,290

## LIST OF REFERENCES CITED BY APPLICANT

## APPLICANT

Akira FUJIMOTO, et al.

FILING DATE  
February 26, 2004GROUP  
1756

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
i	AB						
.	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
/AA/	AO	2002-122702	04/26/2002	Japan		X
/AA/	AP	2001-74919	03/23/2001	Japan		X
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

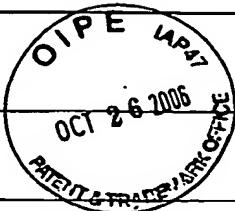
## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	<input type="checkbox"/> Additional References sheet(s) attached

Examiner /Anita Alanko/

Date Considered 04/01/2007

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



	Docket No.: 249406US2SRD	Serial No.: 10/786,290
Inventor: Akira FUJIMOTO, et al.		
LIST OF RELATED CASES CITED BY APPLICANT UNDER 37 CFR 1.56	Filing Date: February 26, 2004	Group: 1756

#### LIST OF RELATED CASES

Examiner Initial	<u>Docket No.</u>	<u>Serial or Patent Number</u>	<u>Filing or Issue Date</u>	<u>Patent App. Publication No.</u>	<u>Inventor or Applicant</u>	<u>Client's Reference No.</u>
/AA/	249406US2SRD	10/786,290	02/26/04		FUJIMOTO, et al.	13G036035-USA-A T7KT-09S1042
/AA/	294294US2SRD DIV	11/493,807	07/27/06		HIEDA, et al.	13G032584-USA-A T7KO-01S1116-D2

Examiner /Anita Alanko/ Date Considered 04/01/2007

\*Present Application; listed for information  
EHK/nle

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249406US2SRD		SERIAL NO. New Application	
				APPLICANT Akira FUJIMOTO, et al.			
LIST OF REFERENCES CITED BY APPLICANT				FILING DATE Herewith		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/AA/	AA	5,779,924	07/14/98	Michael R. KRAMES, et al.			
/AA/	AB	4,554,727	11/26/85	Harry W. DECKMAN, et al.			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
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	AJ						
	AK						
	AL						
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
/AA/	AO	8-167738	06/25/96	JAPAN	YES		X
/AA/	AP	2000-299494	10/24/2000	JAPAN	YES		X
/AA/	AQ	4-354382	12/08/92	JAPAN	YES		X
	AR						
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
/AA/	AW	Y. KANAMORI, et al., "100 NM PERIOD SILICON ANTIREFLECTION STRUCTURES FABRICATED USING A POROUS ALUMINA MEMBRANE MASK", Applied Physics Letters, Vol. 78, No. 2, January 8, 2001, pgs. 142-143					
/AA/	AX	Yoshiaki KANAMORI, et al., "BROADBAND ANTIREFLECTION GRATINGS FOR GLASS SUBSTRATES FABRICATED BY FAST ATOM BEAM ETCHING", Jpn. J. Appl. Phys., Vol. 39, July 15, 2000, pgs. L735-L737					
/AA/	AY	Y. INOMATA, et al., "SURFACE TEXTURING OF LARGE AREA MULTICRYSTALLINE SILICON SOLAR CELLS USING REACTIVE ION ETCHING METHOD", Solar Energy Materials and Solar Cells, Vol. 48, 1997, pgs. 237-242					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Anita Alanko/				Date Considered 04/01/2007			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							